

**Silizium-PIN-Fotodiode**  
**Silicon PIN Photodiode**  
**Lead (Pb) Free Product - RoHS Compliant**

**BPX 61**



**Wesentliche Merkmale**

- Speziell geeignet für Anwendungen im Bereich von 400 nm bis 1100 nm
- Kurze Schaltzeit (typ. 20 ns)
- Hermetisch dichte Metallbauform (ähnlich TO-5)

**Anwendungen**

- Lichtschranken für Gleich- und Wechsellichtbetrieb
- IR-Fernsteuerungen
- Industrieelektronik
- „Messen/Steuern/Regeln“

**Features**

- Especially suitable for applications from 400 nm to 1100 nm
- Short switching time (typ. 20 ns)
- Hermetically sealed metal package (similar to TO-5)

**Application**

- Photointerrupters
- IR-remote controls
- Industrial electronics
- For control and drive circuits

Typ Type	Bestellnummer Ordering Code
BPX 61	Q62702P0025

**Grenzwerte****Maximum Ratings**

<b>Bezeichnung Parameter</b>	<b>Symbol Symbol</b>	<b>Wert Value</b>	<b>Einheit Unit</b>
Betriebs- und Lagertemperatur Operating and storage temperature range	$T_{\text{op}}; T_{\text{stg}}$	- 40 ... + 125	°C
Sperrspannung Reverse voltage	$V_R$	32	V
Verlustleistung, $T_A = 25$ °C Total power dissipation	$P_{\text{tot}}$	250	mW

**Kennwerte** ( $T_A = 25$  °C, Normlicht A,  $T = 2856$  K)**Characteristics** ( $T_A = 25$  °C, standard light A,  $T = 2856$  K)

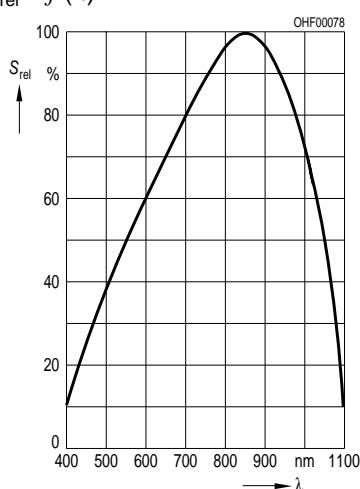
<b>Bezeichnung Parameter</b>	<b>Symbol Symbol</b>	<b>Wert Value</b>	<b>Einheit Unit</b>
Fotoempfindlichkeit, $V_R = 5$ V Spectral sensitivity	$S$	70 ( $\geq 50$ )	nA/lx
Wellenlänge der max. Fotoempfindlichkeit Wavelength of max. sensitivity	$\lambda_{S \text{ max}}$	850	nm
Spektraler Bereich der Fotoempfindlichkeit $S = 10\%$ von $S_{\text{max}}$ Spectral range of sensitivity $S = 10\%$ of $S_{\text{max}}$	$\lambda$	400 ... 1100	nm
Bestrahlungsempfindliche Fläche Radiant sensitive area	$A$	7.00	mm <sup>2</sup>
Abmessung der bestrahlungsempfindlichen Fläche Dimensions of radiant sensitive area	$L \times B$ $L \times W$	2.65 × 2.65	mm × mm
Halbwinkel Half angle	$\varphi$	± 55	Grad deg.
Dunkelstrom, $V_R = 10$ V Dark current	$I_R$	2 ( $\leq 30$ )	nA
Spektrale Fotoempfindlichkeit, $\lambda = 850$ nm Spectral sensitivity	$S_\lambda$	0.62	A/W
Quantenausbeute, $\lambda = 850$ nm Quantum yield	$\eta$	0.90	Electrons Photon
Leerlaufspannung, $E_v = 1000$ lx Open-circuit voltage	$V_O$	375 ( $\geq 320$ )	mV
Kurzschlussstrom, $E_v = 1000$ lx Short-circuit current	$I_{\text{sc}}$	70	μA

**Kennwerte** ( $T_A = 25^\circ\text{C}$ , Normlicht A,  $T = 2856\text{ K}$ )

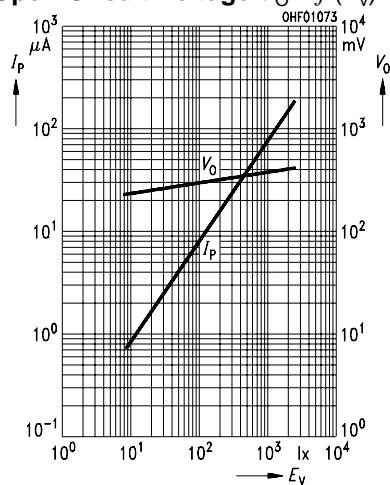
**Characteristics** ( $T_A = 25^\circ\text{C}$ , standard light A,  $T = 2856\text{ K}$ ) (cont'd)

Bezeichnung Parameter	Symbol Symbol	Wert Value	Einheit Unit
Anstiegs- und Abfallzeit des Fotostroms Rise and fall time of the photocurrent $R_L = 50\ \Omega$ ; $V_R = 5\text{ V}$ ; $\lambda = 850\text{ nm}$ ; $I_p = 800\ \mu\text{A}$	$t_r, t_f$	20	ns
Durchlassspannung, $I_F = 100\text{ mA}$ , $E = 0$ Forward voltage	$V_F$	1.3	V
Kapazität, $V_R = 0\text{ V}$ , $f = 1\text{ MHz}$ , $E = 0$ Capacitance	$C_0$	72	pF
Temperaturkoeffizient von $V_O$ Temperature coefficient of $V_O$	$TC_V$	- 2.6	mV/K
Temperaturkoeffizient von $I_{SC}$ Temperature coefficient of $I_{SC}$	$TC_I$	0.18	%/K
Rauschäquivalente Strahlungsleistung Noise equivalent power $V_R = 10\text{ V}$ , $\lambda = 850\text{ nm}$	$NEP$	$4.1 \times 10^{-14}$	$\frac{\text{W}}{\sqrt{\text{Hz}}}$
Nachweisgrenze, $V_R = 10\text{ V}$ , $\lambda = 850\text{ nm}$ Detection limit	$D^*$	$6.6 \times 10^{12}$	$\frac{\text{cm} \times \sqrt{\text{Hz}}}{\text{W}}$

**Relative Spectral Sensitivity**  
 $S_{\text{rel}} = f(\lambda)$



**Photocurrent  $I_P = f(E_v)$ ,  $V_R = 5 \text{ V}$**   
**Open-Circuit Voltage  $V_O = f(E_v)$**

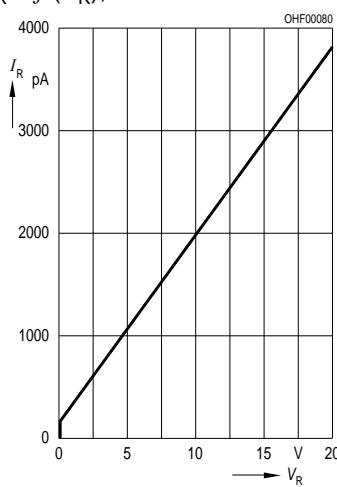


**Total Power Dissipation**  
 $P_{\text{tot}} = f(T_A)$



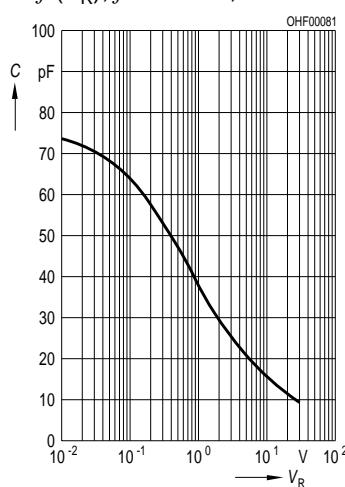
**Dark Current**

$$I_R = f(V_R), E = 0$$



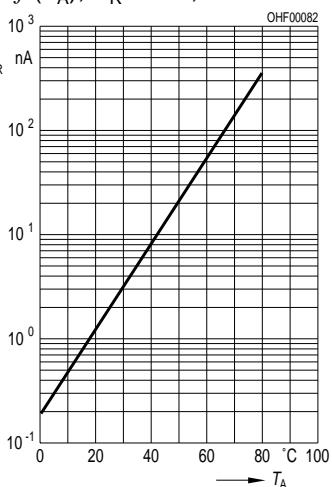
**Capacitance**

$$C = f(V_R), f = 1 \text{ MHz}, E = 0$$



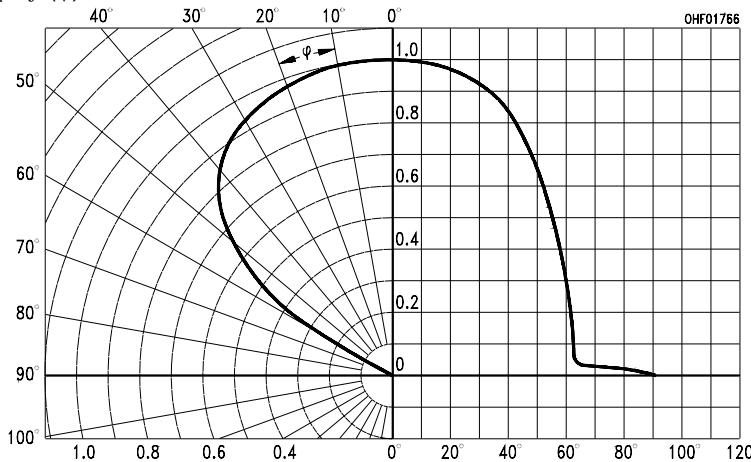
**Dark Current**

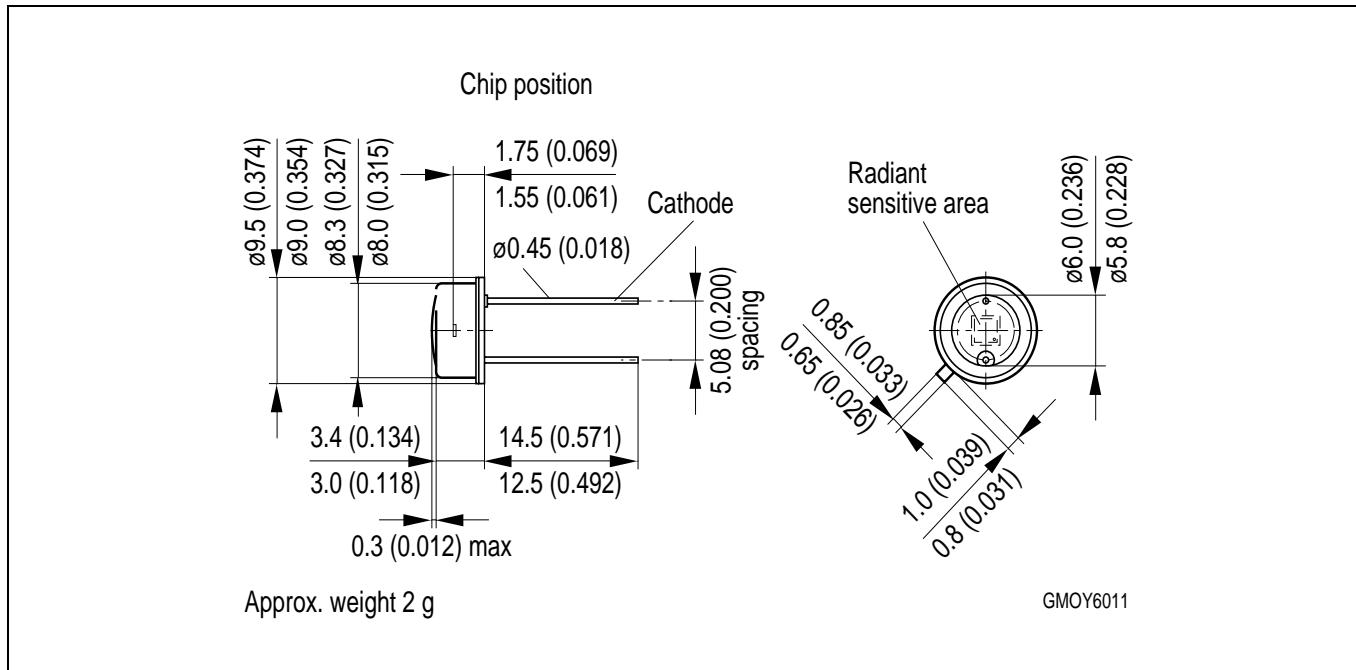
$$I_R = f(T_A), V_R = 5 \text{ V}, E = 0$$



**Directional Characteristics**

$$S_{\text{rel}} = f(\varphi)$$

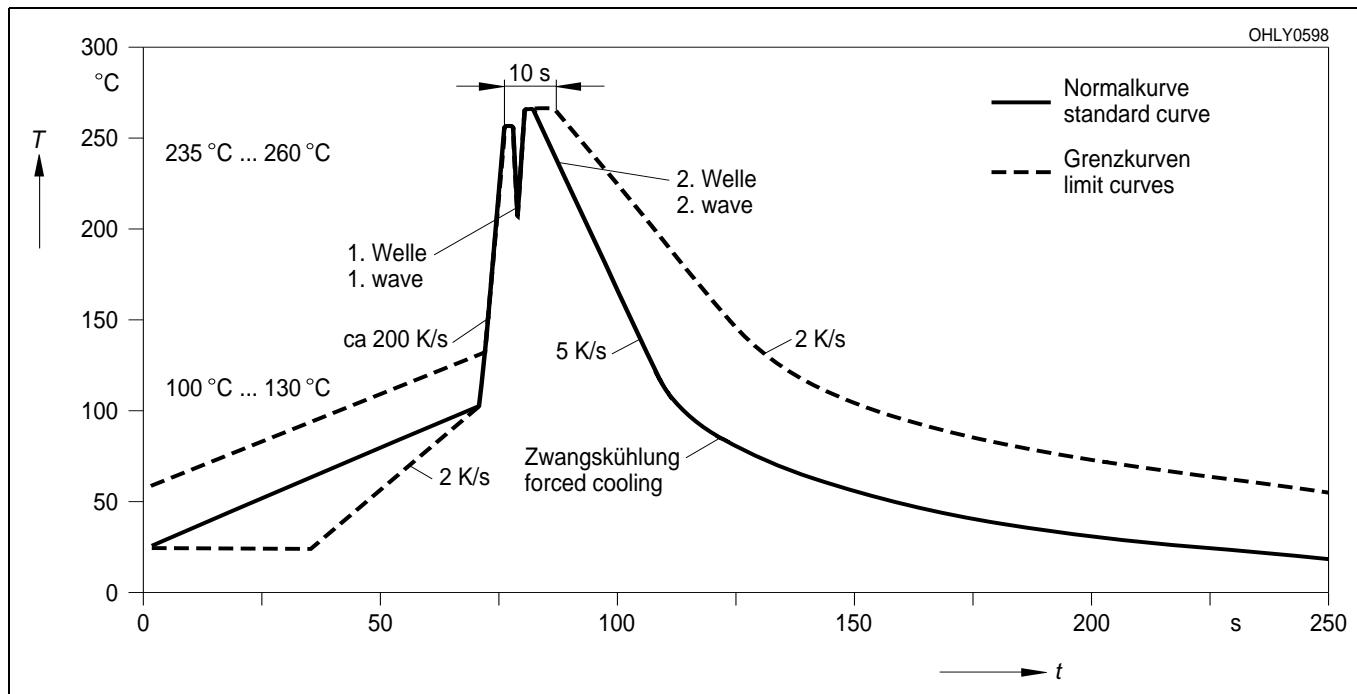


**Maßzeichnung  
Package Outlines**

Maße in mm (inch) / Dimensions in mm (inch).

**Lötbedingungen**  
**Soldering Conditions**  
**Wellenlöten (TTW)**  
**TTW Soldering**

(nach CECC 00802)  
 (acc. to CECC 00802)



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